

Review of Performance: (VEE 235/P1 Digital 2, Fall 2016, 10 students)

Submitted by: Nelchor Permitez Ed. D.

Institutional Student Learning Outcomes (ISLO):

- ILO1: Effective oral communication
- ILO2: Effective written communication
- ILO3: Critical thinking
- ILO4: Problem Solving
- ILO5: Intercultural knowledge and competence
- ILO6: Information literacy
- ILO7: Foundation and skills for life long learning
- ILO8: Quantitative reasoning

Program Student Learning Outcomes (PSLO)

- PL01: Practice Safety and occupational health procedures in the workplace.
- PL02: Use electronic tools and test equipment competently.
- PL03: Interpret schematic diagrams and waveforms.
- PL04: Build electronic projects to a given specification.
- PL05: Practice a career in the Telecomm Industry.
- PL06: Troubleshoot microwave, fiber optics and telephone system.

SLO#	Program SLO#	I, D, M	ISLO	Reflection/Comment
1. Demonstrate knowledge in the operations of register, memory, and microprocessor circuits.	Interpret schematics diagrams and waveforms.	D	7	10 students (8 males; 2 females) out of 10 students (100%) successfully completed this CSLO as measured by using hands on experiments and a written quiz.
2. Show understanding in digital arithmetic	Interpret schematics	D	7	10 students (8 males; 2 females) out of 10 students (100%) successfully completed this CSLO as measured by using hands on experiments and a

counting circuits.	diagrams and waveforms.			written quiz.
3. Exhibit knowledge in data conversion, selector and distributor circuits.	Interpret schematics diagrams and waveforms.	M	7	10 students (8 males; 2 females) out of 10 students (100%) successfully completed this CSLO as measured by using hands on experiments and a written quiz.

Additional observations: Needs more NIDA cards for digital set to accommodate growing number of students in electronics and telecommunication program..

Special comments: 10 students (100%) got a grade of “C” and higher.

Recommendations: Time to purchase new 4 sets of NIDA trainer console, logic probes and test probes of DVM to replace the worn out devices and instruments.

Submitted by:

Date: December 9, 2016

Nelchor Permitez
 Professor Telecomm/Electronics
 Pohnpei Campus